

**Notice of References Cited**

Application/Control No.

10/590,278

Applicant(s)/Patent Under  
Reexamination  
HIRANO ET AL.

Examiner

John Hoffmann

Art Unit

1791

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,430,967 B1	08-2002	Mueller, Peter Michael	65/489
*	B	US-6,105,396 A	08-2000	Glodis et al.	65/377
*	C	US-6,131,413 A	10-2000	Rousseau et al.	65/377
*	D	US-6,286,546 B1	09-2001	Mueller, Peter Michael	137/580
*	E	US-6,210,487 B1	04-2001	Mueller, Peter Michael	118/733
*	F	US-6,516,636 B1	02-2003	Gansicke et al.	65/379
*	G	US-6,698,240 B1	03-2004	Tsumura et al.	65/17.4
*	H	US-6,161,398 A	12-2000	Partus, Fred Paul	65/379
*	I	US-6,484,538 B1	11-2002	Regnier et al.	65/379
*	J	US-2006/0112734 A1	06-2006	Kim et al.	065/489
*	K	US-2006/0179888 A1	08-2006	Digiovanni et al.	065/379
*	L	US-4,813,989	03-1989	Uchiyama et al.	65/489
*	M	US-4,445,918	05-1984	Modone et al.	65/379

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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